

Abstract

A pin card for mounting in a test head of a semiconductor integrated circuit tester to implement test channels of the tester includes contact pins connected to terminals of respective test channels. Each contact pin has a free end for engaging a load board. A conductive switch element is displaceable between a first position, in which the switch element is electrically isolated from one or more of the contact pins, and a second position, in which the switch element is in electrically conductive contact with one or more of the contact pins.

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